

# STM8AF52xx STM8AF62xx Errata sheet

Device limitations for STM8AFx2xx automotive MCUs featuring up to 128 Kbytes of flash program memory

#### Silicon identification

This errata sheet applies to the STMicroelectronics STM8AF526x/8x/Ax and STM8AF6269/8x/Ax devices. The full list of part numbers is given in *Table 2*.

The products can be identified as shown in *Table 1*:

- By the revision code marked below the sales type on the device package
- By the last three digits of the Internal sales type printed on the box label

**Table 1. Device identification** 

Sales type	Revision code marked on the device <sup>(1)</sup>
STM8AF52xx	U, T
STM8AF6269/8x/Ax	U, T

<sup>1.</sup> Refer to the device datasheet for details on how to identify the revision code according to the packages.

#### **Table 2. Device summary**

Reference	Part number		
STM8AF526x/8x/Ax (with CAN)	STM8AF5268, STM8AF5269, STM8AF5286, STM8AF5288, STM8AF5289, STM8AF528A, STM8AF52A6, STM8AF52A8, STM8AF52A9, STM8AF52AA		
STM8AF6269/8x/Ax	STM8AF6269, STM8AF6286, STM8AF6288, STM8AF6289, STM8AF628A, STM8AF62A6, STM8AF62A8, STM8AF62A9, STM8AF62AA		

August 2025 ES0144 Rev 8 1/29

### **Contents**

1	Prod	luct evol	ution	. 6		
2	Silic	Silicon limitations 8				
	2.1	Core .		8		
		2.1.1	Activation level (AL) bit not functional in Halt mode	8		
		2.1.2	JRIL and JRIH instructions not available	8		
		2.1.3	Main CPU execution is not resumed after an ISR resets the AL bit	8		
		2.1.4	Unexpected DIV/DIVW instruction result in ISR	9		
		2.1.5	Wait for event instruction (WFE) not available	9		
		2.1.6	Interrupt service routine (ISR) executed with priority of main process	. 10		
	2.2	System		. 10		
		2.2.1	HSI RC oscillator cannot be switched off in Run mode	. 10		
		2.2.2	LSI oscillator remains on in Active-halt mode when the AWU unit uses the HSE as input clock			
		2.2.3	Failure in CAN communication during bootloader execution	. 10		
		2.2.4	RAM modified after reset by embedded bootloader	. 11		
		2.2.5	Flash / EEPROM memory is read incorrectly after wake-up from power down mode			
		2.2.6	V <sub>DD</sub> rise-time rate for 100mV < V <sub>DD</sub> < 1V	. 12		
		2.2.7	Write access to EEPROM/flash may fail at high speeds and high temperatures 12			
	2.3	Timer p	eripheral	. 13		
		2.3.1	Corruption of read sequence for the 16-bit counter registers	. 13		
	2.4	I <sup>2</sup> C peri	pheral	. 13		
		2.4.1	I <sup>2</sup> C event management	. 13		
		2.4.2	Corrupted last received data in I <sup>2</sup> C Master Receiver mode	. 14		
		2.4.3	Wrong behavior of I <sup>2</sup> C peripheral in Master mode after misplaced STOP	. 15		
		2.4.4	Violation of I <sup>2</sup> C "setup time for repeated START condition" parameter	. 15		
		2.4.5	In I <sup>2</sup> C slave "NOSTRETCH" mode, underrun errors may not be detect and may generate bus errors			
		2.4.6	I <sup>2</sup> C pulse missed	. 16		
	2.5	UART p	peripheral	. 18		
		2.5.1	PE testing issue in USART mode (UART1/UART3)	. 18		
		2.5.2	LIN mode: LIN header error when automatic resynchronization is enabled	. 18		

		2.5.3	LIN mode: framing error with data byte 0x00
		2.5.4	LIN mode: framing error when receiving an identifier (ID)
		2.5.5	LIN mode: parity error when receiving an identifier (ID)
		2.5.6	LIN mode: OR flag not correctly set in LIN Master mode19
	2.6	SPI pe	eripheral
		2.6.1	Last bit too short if SPI is disabled during communication
		2.6.2	Busy flag is unreliable when the SPI is a master simplex receive-only mode
		2.6.3	CRC may be corrupted by SPI configuration or other bus transfers 20
		2.6.4	Anticipated communication upon SPI transit from slave receiver to master
		2.6.5	BSY bit may stay high at the end of data transfer in slave mode 21
	2.7	beCAN	N peripheral
		2.7.1	beCAN transmission error when sleep mode is entered during transmission or reception
		2.7.2	beCAN woken up from sleep mode with automatic wake-up interrupt . 22
		2.7.3	beCAN time triggered communication mode not supported22
		2.7.4	beCAN transmitted data corruption
		2.7.5	beCAN read error in slow mode
		2.7.6	Write in beCAN paged registers ignored
3	Impo	ortant s	ecurity notice
4	Revi	sion his	story



### List of tables

	Device identification	
Table 2.	Device summary	. 1
Table 3.	Product evolution summary	. 6
Table 4.	V <sub>DD</sub> rise-time and fall-time rates	12
	Document revision history	



### List of figures



### 1 Product evolution

*Table 3* gives a summary of the fix status.

Legend for *Table 3*: A = workaround available; N = no workaround available; P = partial workaround available, '-' = fixed.

Table 3. Product evolution summary

Section	Limitation		
	Section 2.1.1: Activation level (AL) bit not functional in Halt mode	N	
	Section 2.1.2: JRIL and JRIH instructions not available	N	
	Section 2.1.3: Main CPU execution is not resumed after an ISR resets the AL bit	Α	
Core	Section 2.1.4: Unexpected DIV/DIVW instruction result in ISR	Α	
	Section 2.1.5: Wait for event instruction (WFE) not available	N	
	Section 2.1.6: Interrupt service routine (ISR) executed with priority of main process	N	
	Section 2.2.1: HSI RC oscillator cannot be switched off in Run mode	N	
	Section 2.2.2: LSI oscillator remains on in Active-halt mode when the AWU unit uses the HSE as input clock	N	
	Section 2.2.3: Failure in CAN communication during bootloader execution		
System	Section 2.2.4: RAM modified after reset by embedded bootloader		
	Section 2.2.5: Flash / EEPROM memory is read incorrectly after wake- up from power- down mode		
	Section 2.2.6: V <sub>DD</sub> rise-time rate for 100mV < V <sub>DD</sub> < 1V	N	
	Section 2.2.7: Write access to EEPROM/flash may fail at high speeds and high temperatures	А	
Timer peripheral	Section 2.3.1: Corruption of read sequence for the 16-bit counter registers		
	Section 2.4.1: I <sup>2</sup> C event management	Α	
l <sup>2</sup> C peripheral	Section 2.4.2: Corrupted last received data in I <sup>2</sup> C Master Receiver mode		
	Section 2.4.3: Wrong behavior of I <sup>2</sup> C peripheral in Master mode after misplaced STOP		
	Section 2.4.4: Violation of I <sup>2</sup> C "setup time for repeated START condition" parameter	Α	
	Section 2.4.5: In I <sup>2</sup> C slave "NOSTRETCH" mode, underrun errors may not be detected and may generate bus errors		
	Section 2.4.6: I <sup>2</sup> C pulse missed	-	

Table 3. Product evolution summary (continued)

Section	Limitation		
	Section 2.5.1: PE testing issue in USART mode (UART1/UART3)	Ν	
	Section 2.5.2: LIN mode: LIN header error when automatic resynchronization is enabled	1	
UART peripheral	Section 2.5.3: LIN mode: framing error with data byte 0x00	N	
репрпетаг	Section 2.5.4: LIN mode: framing error when receiving an identifier (ID)	N	
	Section 2.5.5: LIN mode: parity error when receiving an identifier (ID)	N	
	Section 2.5.6: LIN mode: OR flag not correctly set in LIN Master mode	N	
	Section 2.6.1: Last bit too short if SPI is disabled during communication	Α	
SPI peripheral	Section 2.6.2: Busy flag is unreliable when the SPI is a master simplex receive-only mode	N	
	Section 2.6.3: CRC may be corrupted by SPI configuration or other bus transfers	А	
	Section 2.6.4: Anticipated communication upon SPI transit from slave receiver to master	Α	
	Section 2.6.5: BSY bit may stay high at the end of data transfer in slave mode	Α	
beCAN peripheral	Section 2.7.1: beCAN transmission error when sleep mode is entered during transmission or reception	А	
	Section 2.7.2: beCAN woken up from sleep mode with automatic wake- up interrupt	А	
	Section 2.7.3: beCAN time triggered communication mode not supported	N	
	Section 2.7.4: beCAN transmitted data corruption	-	
	Section 2.7.5: beCAN read error in slow mode	Α	
	Section 2.7.6: Write in beCAN paged registers ignored	Α	

#### 2 Silicon limitations

#### 2.1 Core

#### 2.1.1 Activation level (AL) bit not functional in Halt mode

#### **Description**

The AL bit is not supported in Halt mode. In particular, when the AL bit of the CFG\_GCR register is set, the CPU does not return to Halt mode after exiting an interrupt service routine (ISR). It returns to the main program and executes the next instruction after the HALT instruction. The AL bit is supported correctly in WFI mode.

#### Workaround

No workaround available.

No fix is planned for this limitation.

#### 2.1.2 JRIL and JRIH instructions not available

#### **Description**

JRIL (jump if port INT pin = 0) and JRIH (jump if port INT pin = 1) are not supported by the devices covered by this datasheet. These instructions perform conditional jumps: JRIL and JRIH jump if one of the external interrupt lines is low and high, respectively. JRIL is equivalent to an unconditional jump and JRIH is equivalent to a NOP.

For further details on these instructions, refer to the STM8 CPU programming manual (PM0044) on www.st.com.

#### Workaround

No workaround available.

No fix is planned for this limitation.

#### 2.1.3 Main CPU execution is not resumed after an ISR resets the AL bit

#### **Description**

If the CPU is in wait for interrupt state and the AL bit is set, the CPU returns to wait for interrupt state after executing an ISR. To continue executing the main program, the AL bit must be reset by the ISR. When AL is reset just before exiting the ISR, the CPU may remain stalled.

#### Workaround

Reset the AL bit at least two instructions before the IRET instruction.

No fix is planned for this limitation.

#### 2.1.4 Unexpected DIV/DIVW instruction result in ISR

#### **Description**

In very specific conditions, a DIV/DIVW instruction may return a false result when executed inside an interrupt service routine (ISR). This error occurs when the DIV/DIVW instruction is interrupted and a second interrupt is generated during the execution of the IRET instruction of the first ISR. Under these conditions, the DIV/DIVW instruction executed inside the second ISR, including function calls, may return an unexpected result.

The applications that do not use the DIV/DIVW instruction within ISRs are not impacted.

#### Workaround 1

If an ISR or a function called by this routine contains a division operation, the following assembly code should be added inside the ISR before the DIV/DIVW instruction:

```
push cc
pop a
and a,#$BF
push a
pop cc
```

This sequence should be placed by C compilers at the beginning of the ISR using DIV/DIVW. Refer to the compiler documentation for details on the implementation and control of automatic or manual code insertion.

#### Workaround 2

To optimize the number of cycles added by workaround 1, it is possible to use this workaround instead. Workaround 2 can be used in applications with fixed interrupt priorities, identified at the program compilation phase:

```
push #value
pop cc
```

where bits 5 and 3 of #value have to be configured according to interrupt priority given by I1 and I0, and bit 6 kept cleared.

In this case, compiler workaround 1 has to be disabled by using compiler directives.

No fix is planned for this limitation.

#### 2.1.5 Wait for event instruction (WFE) not available

#### **Description**

The WFE instruction is not implemented in the devices covered by this errata sheet. This instruction is used to synchronize the device with external computing resources. For further details on this instruction, refer to the STM8 CPU programming manual (PM0044) on <a href="https://www.st.com">www.st.com</a>.

#### Workaround

No workaround available.

No fix is planned for this limitation.



ES0144 Rev 8 9/29

#### 2.1.6 Interrupt service routine (ISR) executed with priority of main process

#### **Description**

If an interrupt is cleared or masked when the context saving has already started, the corresponding ISR is executed with the priority of the main process. The next interrupt request can interrupt execution of the service routine.

#### Workaround

At the beginning of the interrupt routine, change the current priority level in the CCR register by software.

#### 2.2 System

#### 2.2.1 HSI RC oscillator cannot be switched off in Run mode

#### **Description**

The internal 16 MHz RC oscillator cannot be switched off in Run mode, even if the HSIEN bit is programmed to 0.

#### Workaround

No workaround available.

No fix is planned for this limitation.

## 2.2.2 LSI oscillator remains on in Active-halt mode when the AWU unit uses the HSE as input clock

#### **Description**

When the auto-wakeup unit (AWU) uses the high speed external clock (HSE) divided by the prescaler (clock source enabled by setting the CKAWUSEL option bit), the LSI RC oscillator is not switched off when the device operates in Active-halt mode with the main voltage regulator (MVR) on. This causes negligible extra power consumption compared to the total consumption of the MCU in Active-halt mode with the MVR on.

#### Workaround

No workaround available.

No fix is planned for this limitation.

#### 2.2.3 Failure in CAN communication during bootloader execution

#### **Description**

The CAN filter registers are not initialized by the bootloader. This can lead to failure during communication with the bootloader.

#### Workaround

No workaround available. Fixed in silicon revision T and U.

#### 2.2.4 RAM modified after reset by embedded bootloader

#### **Description**

After each reset, the byte located at RAM address 0x99 is modified by the embedded bootloader even if the bootloader is disabled by option byte. So the RAM content at address 0x99 is not maintained after reset. The limitation is present only in device revision X.

#### Workaround

No workaround available. Do not use the byte in RAM at address 0x99 to store variables which should be unchanged after device reset.

## 2.2.5 Flash / EEPROM memory is read incorrectly after wake-up from power-down mode

#### **Description**

If flash/EEPROM memory has been put in power-down mode ( $I_{DDQ}$ ), the first read access after wake-up could return incorrect content when the number of wait states is configured to 0

By default, the flash/EEPROM memory is put in  $I_{DDQ}$  mode when the MCU enters Halt mode and depending on the FLASH\_CR1 register settings made by software, the flash/EEPROM may be forced to  $I_{DDQ}$  mode during active halt mode.

As a consequence, the following behavior may be seen on some devices:

- After wake-up from Low-power mode, with flash memory in I<sub>DDQ</sub> mode, program execution gets lost due to an incorrect read of the vector table.
- Code reads an incorrect value from flash/EEPROM memory, when forced in I<sub>DDQ</sub> mode.
- Reset could be forced by an illegal opcode execution due to incorrect read of instruction.

Note: The use of the watchdog helps the application to recover in case of failure.

#### Workaround 1

Keep the flash/EEPROM in operating mode when the MCU is put in Halt mode or Active-halt mode. This is done by configuring both the HALT and AHALT bits in the FLASH\_CR1 register before executing a HALT instruction to prevent the flash/EEPROM entering  $I_{DDQ}$  mode.

Set HALT (bit 3) to '1':

- 0: Flash in power-down mode when MCU is in Halt mode
- 1: Flash in operating mode when MCU is in Halt mode

Keep AHALT (bit 2) at '0':

- 0: Flash in operating mode when MCU is in Active-halt mode
- 1: Flash in power-down when MCU is in Active-halt mode

Please refer to the datasheet for details on the impact on current consumption and wake-up time.

57

ES0144 Rev 8 11/29

#### Workaround 2

Set the number of wait states to 1.

This may be done by setting OPT7 to 0x01

#### 2.2.6 $V_{DD}$ rise-time rate for 100mV < $V_{DD}$ < 1V

#### **Description**

The product datasheet did not specify the  $V_{DD}$  rise-time initial conditions as the  $V_{DD}$  rise-time was implicitly specified for a  $V_{DD}$  starting from 0V. Nevertheless, we observed that some very specific applications could have a  $V_{DD}$  starting from a residual voltage already above 0V and thus require that we explicitly specify these conditions.

The  $t_{VDD}$  parameter must stay below 50µs/V when  $V_{DD}$  is rising from 100mV to 1V.

Symbol Min Unit **Parameter** Conditions Тур Max 2<sup>(1)</sup>  $V_{DD} < 100 \text{mV}$  $2^{(1)}$ 50<sup>(1)</sup>  $100 \text{mV} < V_{DD} < 1 \text{V}$ V<sub>DD</sub> rise-time rate us/V  $t_{VDD}$ 2<sup>(1)</sup> ∞  $V_{DD} > 1V$ 2(1) V<sub>DD</sub> fall-time rate

Table 4. V<sub>DD</sub> rise-time and fall-time rates

#### Workaround

Not applicable.

## 2.2.7 Write access to EEPROM/flash may fail at high speeds and high temperatures

#### **Description**

During write into the data EEPROM or program flash, a corruption on code flash may occur.

This failure may occur when following conditions are fulfilled:

- Device operates at high speed, above 20 MHz
- Device operates at high temperatures

Under those circumstances, write may be performed into the code memory instead of data memory, or into different address of the code memory.

#### Workaround

Use system frequency of 20 MHz or lower during the write operation.

For systems running at higher speed, system frequency could be divided by 2 using CPUDIV[2:0] bits in the CLK\_CKDIVR before write operation and set back once write operation is finished.

<sup>1.</sup> Guaranteed by design, not tested in production.

#### 2.3 Timer peripheral

#### 2.3.1 Corruption of read sequence for the 16-bit counter registers

#### **Description**

An 8-bit buffer is implemented for reading the 16-bit counter registers. Software must read the MS byte first, after which the LS byte value is buffered automatically (see *Figure 1*). This buffered value remains unchanged until the 16-bit read sequence is completed.

When any multicycle instruction precedes the read of the LSB, the content of the buffer is lost, and the second read returns the immediate content of the counter directly.

Beginning of the sequence

Read
MS byte
I shared sequence

Read
MS byte
I shared
I LS byte
I shared
I sh

Figure 1. 16-bit read sequence for the counter (TIMx CNTR)

#### Workaround

Do not use multicycle instructions before reading the LSB.

No fix is planned for this limitation.

### 2.4 I<sup>2</sup>C peripheral

### 2.4.1 I<sup>2</sup>C event management

#### **Description**

As described in the I<sup>2</sup>C section of the STM8S and STM8A microcontroller reference manual (RM0016), the application firmware has to manage several software events before the current byte is transferred. If the EV7, EV7\_1, EV6\_1, EV6\_3, EV2, EV8, and EV3 events are not managed before the current byte is transferred, problems may occur such as receiving an extra byte, reading the same data twice, or missing data.

#### Workaround

When the EV7, EV7\_1, EV6\_1, EV6\_3, EV2, EV8, and EV3 events cannot be managed before the current byte transfer, and before the acknowledge pulse when the ACK control bit changes, it is recommended to use I<sup>2</sup>C interrupts in nested mode and to make them uninterruptible by increasing their priority to the highest priority in the application.

No fix is planned for this limitation.

#### 2.4.2 Corrupted last received data in I<sup>2</sup>C Master Receiver mode

#### **Conditions**

In Master Receiver mode, when the communication is closed using method 2, the content of the last read data may be corrupted. The following two sequences are concerned by the limitation:

- Sequence 1: transfer sequence for master receiver when N = 2
  - a) BTF = 1 (Data N-1 in DR and Data N in shift register)
  - b) Program STOP = 1
  - c) Read DR twice (Read Data N-1 and Data N) just after programming the STOP bit.
- Sequence 2: transfer sequence for master receiver when N > 2
  - a) BTF = 1 (Data N-2 in DR and Data N-1 in shift register)
  - b) Program ACK = 0
  - c) Read Data N-2 in DR
  - d) Program STOP bit to 1
  - e) Read Data N-1.

#### **Description**

The content of the shift register (data N) is corrupted (data N is shifted 1 bit to the left) if the user software is not able to read data N-1 before the STOP condition is generated on the bus. In this case, reading data N returns a wrong value.

#### Workarounds

- Workaround 1
  - Sequence 1

When sequence 1 is used to close communication using method 2, mask all active interrupts between STOP bit programming and Read data N-1.

Sequence 2

When sequence 2 is used to close communication using method 2, mask all active interrupts between Read data N-2, STOP bit programming and Read data N-1.

Workaround 2

Manage I2C RxNE and TxE events with interrupts of the highest priority level, so that the condition BTF = 1 never occurs.

## 2.4.3 Wrong behavior of I<sup>2</sup>C peripheral in Master mode after misplaced STOP

#### **Description**

The I<sup>2</sup>C peripheral does not enter Master mode properly if a misplaced STOP is generated on the bus. This can happen in the following conditions:

- If a void message is received (START condition immediately followed by a STOP): the BERR (bus error) flag is not set, and the I<sup>2</sup>C peripheral is not able to send a START condition on the bus after writing to the START bit in the I2C\_CR2 register.
- In the other cases of a misplaced STOP, the BERR flag is set in the IC2\_CR2 register.
   If the START bit is already set in I2C\_CR2, the START condition is not correctly generated on the bus, and can create bus errors.

#### Workaround

In the I<sup>2</sup>C standard, it is not allowed to send a STOP before the full byte is transmitted (8 bits + acknowledge). Other derived protocols like CBUS allow it, but they are not supported by the I<sup>2</sup>C peripheral.

In case of noisy environment in which unwanted bus errors can occur, it is recommended to implement a timeout to ensure that the SB (start bit) flag is set after the START control bit is set. In case the timeout has elapsed, the peripheral must be reset by setting the SWRST bit in the I2C\_CR2 control register. The I<sup>2</sup>C peripheral should be reset in the same way if a BERR is detected while the START bit is set in I2C\_CR2.

No fix is planned for this limitation.

### 2.4.4 Violation of I<sup>2</sup>C "setup time for repeated START condition" parameter

#### **Description**

In case of a repeated Start, the "setup time for repeated START condition" parameter (named  $t_{SU(STA)}$  in the datasheet and Tsu:sta in the  $I^2C$  specifications) may be slightly violated when the  $I^2C$  operates in Master Standard mode at a frequency ranging from 88 to 100 kHz.  $t_{SU(STA)}$  minimum value may be 4  $\mu s$  instead of 4.7  $\mu s$ .

The issue occurs under the following conditions:

- The I<sup>2</sup>C peripheral operates in Master Standard mode at a frequency ranging from 88 to 100 kHz (no issue in Fast mode)
- 2. and the SCL rise time meets one of the following conditions:
  - The slave does not stretch the clock and the SCL rise time is more than 300 ns (the issue cannot occur when the SCL rise time is less than 300 ns).
  - or the slave stretches the clock.

#### Workaround

Reduce the frequency down to 88 kHz or use the I<sup>2</sup>C Fast mode if it is supported by the slave.

4

ES0144 Rev 8 15/29

## 2.4.5 In I<sup>2</sup>C slave "NOSTRETCH" mode, underrun errors may not be detected and may generate bus errors

#### **Description**

The data valid time ( $t_{VD;DAT}$ ,  $t_{VD;ACK}$ ) described by the  $I^2C$  specifications may be violated as well as the maximum current data hold time ( $t_{HD;DAT}$ ) under the conditions described below. In addition, if the data register is written too late and close to the SCL rising edge, an error may be generated on the bus: SDA toggles while SCL is high. These violations cannot be detected because the OVR flag is not set (no transmit buffer underrun is detected).

This issue occurs under the following conditions:

- 1. The I<sup>2</sup>C peripheral operates In Slave transmit mode with clock stretching disabled (NOSTRETCH=1)
- 2. and the application is late to write the DR data register, but not late enough to set the OVR flag (the data register is written before the SCL rising edge).

#### Workaround

If the master device supports it, use the clock stretching mechanism by programming the bit NOSTRETCH=0 in the I2C CR1 register.

If the master device does not support it, ensure that the write operation to the data register is performed just after TXE or ADDR events. The user can use an interrupt on the TXE or ADDR flag and boost its priority to the higher level.

Using the "NOSTRETCH" mode with a slow I<sup>2</sup>C bus speed can prevent the application from being late to write the DR register (second condition).

Note:

The first data to be transmitted must be written into the data register after the ADDR flag is cleared, and before the next SCL rising edge, so that the time window to write the first data into the data register is less than  $t_{\rm LOW}$ .

If this is not possible, a possible workaround can be the following:

- 1. Clear the ADDR flag
- 2. Wait for the OVR flag to be set
- Clear OVR and write the first data.

The time window for writing the next data is then the time to transfer one byte. In that case, the master must discard the first received data.

### 2.4.6 I<sup>2</sup>C pulse missed

#### **Description**

When the I<sup>2</sup>C interface is used for long transmit/receive transactions, the MCU may return a NACK somewhere during the transaction instead of returning an ACK for all data. The received data may also be corrupted. In Master mode the I<sup>2</sup>C may not detect an incoming ACK. This is due to a weakness in the noise filter of the I/O pad which in certain conditions may cause the STM8 I<sup>2</sup>C to miss a pulse.

The workaround described below is not a clean solution. However, the limitation is fixed in revisions T and U.

4

#### Workaround

Since data corruption is caused by noise generated by the CPU, CPU activity should be minimized during data reception and/or transmission. This is done by performing physical data transmission (Master mode) and reception (slave mode) in WFI state (wait for interrupt).

To allow the device to be woken up from WFI, I<sup>2</sup>C transmission and reception routines must be implemented through interrupt routines instead of polling mechanisms. Receive and transmit interrupts (received data processing) must be triggered only by the BTF bit flag (byte transfer finished) in the I2C\_SR1 register. This flag indicates that the I<sup>2</sup>C is in stretched state (data transfers are stretched on the bus).

Clock stretching must be enabled to allow data transfers from the slave to be stopped and to allow the CPU to be woken up to read the received byte.

To recover from possible errors, periodically check if the I<sup>2</sup>C does not remain in busy state for too long (BUSY bit set in I2C\_SR3 register). If so, it should be reinitialized.

Example of I<sup>2</sup>C slave code:

```
//...
//-----
void main()
{
    Init_I2C(); // init I2C to use interrupts: ITBUFEN=0, ITEVTEN=1,
ITERREN=1
    while(1)
```

**4** 

ES0144 Rev 8 17/29

#### 2.5 UART peripheral

#### 2.5.1 PE testing issue in USART mode (UART1/UART3)

#### **Description**

When the RXNE flag is not polled, the device is in overrun condition, and the PE flag does not rise in case of a parity error. The flag rises only for the last data which have been correctly received.

#### Workaround

No workaround available.

No fix is planned for this limitation.

## 2.5.2 LIN mode: LIN header error when automatic resynchronization is enabled

#### **Description**

If UART3 is configured in LIN slave mode (LSLV bit set in UART3\_CR6 register) and the automatic resynchronization is enabled (LASE bit set in UART3\_CR6), the LHE flag may be set instead of LHDF flag when receiving a valid header.

This limitation is fixed in silicon revision U and T.

#### Workaround

No workaround available.

#### 2.5.3 LIN mode: framing error with data byte 0x00

#### **Description**

If the UART3 interface is configured in LIN slave mode, and the active mode with break detection length is set to 11 (LBDL bit of UART3\_CR4 register set to 1), FE and RXNE flags are not set when receiving a 0x00 data byte with a framing error, followed by a recessive state. This occurs only if the dominant state length is between 9.56 and 10.56 times the baud rate.

#### Workaround

The LIN software driver can handle this exceptional case by implementing frame timeouts to comply with the LIN standard. This method has been implemented in ST LIN 2.1 driver package which passed the LIN compliance tests.

#### 2.5.4 LIN mode: framing error when receiving an identifier (ID)

#### **Description**

If an ID framing error occurs when the UART3, configured in LIN mode, is in active mode, both the LHE and LHDF flags are set at the end of the LIN header with an ID framing error.

#### Workaround

The LIN software driver can handle this case by checking both LHE and LHDF flags upon header reception.

#### 2.5.5 LIN mode: parity error when receiving an identifier (ID)

#### **Description**

If an ID parity error occurs, the UART3, configured in LIN mode, wakes up from mute mode and both LHE and LHDF are set at the end of the LIN header with parity error. The PE flag is also set.

#### Workaround

The LIN software driver can handle this case by checking all flags upon header reception.

No fix is planned for this limitation.

#### 2.5.6 LIN mode: OR flag not correctly set in LIN Master mode

#### **Description**

When the UART operates in LIN Master mode, the OR flag is not set if an overrun condition occurs. This is valid for UART1 and UART3.

#### Workaround

The LIN software driver can detect this case through a LIN protocol error.

No fix is planned for this limitation.

#### 2.6 SPI peripheral

#### 2.6.1 Last bit too short if SPI is disabled during communication

#### **Description**

When the SPI interface operates in Master mode and the baud rate generator prescaler is equal to 2, the SPI is disabled during ongoing communications, and the data and clock output signals are switched off at the last strobing edge of the SPI clock.

As a consequence, the length of the last bit is out of range and its reception on the bus is not ensured.

#### Workaround

Check if a communication is ongoing before disabling the SPI interface. This can be done by monitoring the BSY bit in the SPI SR register.

## 2.6.2 Busy flag is unreliable when the SPI is a master simplex receive-only mode

#### **Description**

When the master is simplex receive-only mode, it provides the clock immediately after setting the SPE bit in the SPI\_CR1 register. In this case, the clock is provided until the SPE bit is cleared, meaning that the SPI is always busy because it is in receive-only mode and continuously receives data. As a result, the BSY flag of the SPI\_SR register is unreliable to detect the SPI status when the SPI is in master receive-only mode.

#### Workaround

None. The reference manual has been updated to explain how to handle this mode.

#### 2.6.3 CRC may be corrupted by SPI configuration or other bus transfers

#### **Description**

When the CRC is enabled (CRCEN bit set in the SPI\_CR2 register), the CRC calculation may be corrupted, or unreliable if one of the following conditions is met:

- The CPHA bit, the CPOL bit, or the CRCPOLY bitfield is configured.
- The value of the polynomial programmed in the CRCPOLY bitfield of the SPI\_CRCPR register is even.
- A bus transfer is ongoing with another slave, or parasitic pulses are observed on the SCK output when the SPI is enabled in slave mode but not selected for communication.

#### Workaround

Both the master and slave must reset and resynchronize their CRC calculation just before starting a new transfer secured by CRC.

Apply the following measures:

- Always configure the CPHA bit, the CPOL bit, and the CRCPOLY bitfield before setting the CRCEN bit.
- Always program an odd polynomial value in the CRCPOLY bitfield of the SPI\_CRCPR register (bit 0 set).
- Before starting any transfer secured by CRC calculation, clear and set again the CRCEN bit while the SPI is disabled.

## 2.6.4 Anticipated communication upon SPI transit from slave receiver to master

#### **Description**

The communication clock starts upon setting the MSTR bit even though the SPI is disabled, if transiting from the enabled slave receive-only mode (RXONLY = 1) to whatever master mode.

#### Workaround

Set the MSTR and SPE bits of the SPI\_CR1 register simultaneously, which forces the immediate start of the communication clock.

If the master is configured in transmitter mode (full-duplex or simplex), load the first data into the SPI DR data register before configuring the SPI CR1 register.

#### 2.6.5 BSY bit may stay high at the end of data transfer in slave mode

#### **Description**

The BSY flag may sporadically remain high at the end of a data transfer in slave mode. The issue appears when an accidental synchronization happens between the internal CPU clock and the external SCK clock provided by the master.

This is related to the end of data transfer detection while the SPI is enabled in slave mode.

As a consequence, the end of the data transaction may be not recognized when the software needs to monitor it (for example at the end of a session before entering the low-power mode or before the direction of the data line has to be changed at half duplex bidirectional mode). The BSY flag is unreliable to detect the end of any data sequence transaction.

#### Workaround

Depending on SPI operating mode, use the following means for detecting the end of transaction:

- When NSS hardware management is applied and NSS signal is provided by master, use NSS input.
- In SPI receiving mode, use the corresponding RXNE event flag.
- In SPI transmit-only mode, use the BSY flag in conjunction with a timeout expiry event. Set the timeout such as to exceed the expected duration of the last data frame and start it upon TXE event that occurs with the second bit of the last data frame. The end of the transaction corresponds to either the BSY flag becoming low or the timeout expiry, whichever happens first.

Prefer one of the first two measures to the third as they are simpler and less constraining. Alternatively, apply the following sequence to ensure reliable operation of the BSY flag in SPI transmit mode:

- 1. Write the last data to the data register.
- 2. Poll TXE until it becomes high to ensure the data transfer has started.
- 3. Disable SPI by clearing SPE while the last data transfer is still ongoing.
- 4. Poll the BSY bit until it becomes low.
- 5. The BSY flag works correctly and can be used to recognize the end of the transaction.

Note:

This sequence can be used only when the CPU has enough performance to disable the SPI after a TXE event is detected, while the data frame transfer is still ongoing. It is impossible to achieve it when the ratio between CPU and SPI clock is low. In this specific case, the BSY check timeout can be measured by executing a fixed number of dummy instructions (such as NOP), corresponding to the time necessary to complete the data frame transaction.



ES0144 Rev 8 21/29

#### 2.7 beCAN peripheral

## 2.7.1 beCAN transmission error when sleep mode is entered during transmission or reception

#### **Description**

If beCAN Sleep operating mode entry is requested while a transmission or reception is ongoing, or a transmission request is pending, the CAN\_TX pin may have a spurious behavior, incompliant with the CAN protocol in case an error occurs on the bus.

No error frame will be sent and the device will enter Sleep mode.

#### Workaround

Before requesting Sleep mode, request Initialization mode and wait until Initialization mode is entered.

#### 2.7.2 beCAN woken up from sleep mode with automatic wake-up interrupt

#### Description

Waking up the beCAN from sleep mode using the automatic wake-up interrupt triggers an interrupt on each CAN Rx falling edge until the bus is idle.

#### Workaround

To have a wakeup interrupt triggered only on the first falling edge of the CAN Rx pin, perform the following actions:

- 1. Disable the automatic wakeup interrupt.
- 2. Clear the WKUI flag.
- Disable the sleep mode in the ISR.

#### 2.7.3 beCAN time triggered communication mode not supported

#### **Description**

The time triggered communication mode described in the STM8S and STM8A reference manual (RM00016) is not supported.

TTCM bit must be kept at 0 in the CAN\_MCR register (time triggered communication mode disabled).

#### Workaround

None.

#### 2.7.4 beCAN transmitted data corruption

#### Description

The TGT bit can be set to 1 (CAN\_MTSRH and CAN\_MTSRL registers sent) even if the device is not in time triggered communication mode (TTCM set to 1). This is due to the fact

that the CAN\_MDLCR register reset value is undefined, causing the TGT bit to be set to 1 whatever the value of TTCM. This leads to the corruption of last two data bytes sent.

#### Workaround

TGT bit in CAN\_MDLCR must be initialized to 0 (CAN\_MTSRH and CAN\_MTSRL registers not sent).



#### 2.7.5 beCAN read error in slow mode

#### **Description**

The read byte may be corrupted when the CPU is in slow mode and a FIFO read operation is performed while a message transmission is ongoing. This happens because the transmission mailboxes and the receive FIFOs share the same address/data lines for read and write operations.

#### Workaround

To prevent this problem from occurring, the CPU clock must be the master clock (CLK\_CKDIVR[2:0] = 000b) when the user application starts reading the FIFO (CPU clock divider changed to /1). After the FIFO read operation is complete, the CPU clock divider (slow mode) could be applied again.

#### 2.7.6 Write in beCAN paged registers ignored

#### Description

In very specific conditions, a write to the beCAN paged registers may be ignored. This occurs when the CPU is writing twice or more into beCAN paged registers in consecutive master clock cycles, and during the second or further writes, the CAN 2.0B active core is accessing (read or write) one of the paged registers.

A typical case is when the CPU is writing constants into paged registers (typically a mailbox for transmission) while the CAN 2.0B active core is reading the filters during a frame reception, or writing the FIFO after a frame reception. The beCAN paged registers range is from address 0x5428 to address 0x5437.

Note:

CAN 2.0B active core does not access the paged registers as long as the beCAN is in initialization mode. Therefore, the issue cannot occur while the software is writing into the paged registers to initialize the beCAN (filter configuration, for example).

The CPU write into two paged registers in two consecutive master clock cycles may only happen in case of consecutive single-cycle load and transfer instructions or single-cycle bit operation instructions, when the destination is an address within the range 0x5428 to 0x5437 inside the beCAN peripheral. The instructions are single-cycle if the source is a constant (embedded in instruction opcode) or in the A accumulator (when the same value has to be stored in two or more CAN registers).

#### List of instructions:

MOV longmem, #byte ; LD longmem, A ; CLR longmem



#### **Examples:**

Consecutive MOV instructions with immediate addressing mode

```
MOV 0x5429, #0x08
MOV 0x542a, #0x0d
MOV 0x542b, #0x40
```

Consecutive LD instructions with A register as source

```
LD 0x542d, A
LD 0x542e, A
```

CLR instruction followed by another single-cycle instruction

```
CLR 0x542d
MOV 0x542e, #0x40
```

Mix of single-cycle instructions

```
LD 0x5429, A
MOV 0x542a, #0x0d
```

Consecutive single-cycle bit instruction BSET, BRST, BCPL might also generate the case.

#### List of instructions:

```
BSET longmem, n ; BRES longmem, n ; BCPL longmem, n
```

Another very unlikely case is indirect or indexed addressing with beCAN address loaded in X or Y registers, which also generates single-cycle instructions.

#### List of instructions:

This can also happen with a single 2-cycle LDW instruction, if two consecutive registers are written with a 16-bit data, with X or Y register as source.

#### List of instructions:

```
LDW longmem, X ; LDW longmem, Y
```

#### Example:

LDW 0x542a, X; with X containing 0x0d40.

4

ES0144 Rev 8 25/29

The issue may happen typically if the software is filling paged registers with constants.

#### **Example:**

If the beCAN paged registers are not written with constants, and if beCAN paged registers are written with the value of an 8-bit variable, this is very unlikely to fall into one of these cases, as either 2-cycle instructions are generated by the compiler or an additional instruction is inserted between two beCAN accesses (loading the variable into the A accumulator).

#### Impact on application

When all the specific conditions are met, a corrupted frame may be sent to the CAN bus.

#### Workaround

In the case that the user needs to write consecutively into paged registers, insert a NOP instruction in between each write. The user can make use of inline assembly in C code.

#### **Example:**

```
#define MY_ID (unsigned int) 0x0350
[...]
CAN_P1 = 0x08;
   _asm(nop");
CAN_P2 = (MY_ID >> 6) & 0x1F;
   _asm(nop");
CAN_P3 = (MY_ID << 2) & 0xFC;</pre>
```

No fix is planned for this limitation.

### 3 Important security notice

The STMicroelectronics group of companies (ST) places a high value on product security, which is why the ST product(s) identified in this documentation may be certified by various security certification bodies and/or may implement our own security measures as set forth herein. However, no level of security certification and/or built-in security measures can guarantee that ST products are resistant to all forms of attacks. As such, it is the responsibility of each of ST's customers to determine if the level of security provided in an ST product meets the customer needs both in relation to the ST product alone, as well as when combined with other components and/or software for the customer end product or application. In particular, take note that:

- ST products may have been certified by one or more security certification bodies, such as Platform Security Architecture (www.psacertified.org) and/or Security Evaluation standard for IoT Platforms (www.trustcb.com). For details concerning whether the ST product(s) referenced herein have received security certification along with the level and current status of such certification, either visit the relevant certification standards website or go to the relevant product page on www.st.com for the most up to date information. As the status and/or level of security certification for an ST product can change from time to time, customers should re-check security certification status/level as needed. If an ST product is not shown to be certified under a particular security standard, customers should not assume it is certified.
- Certification bodies have the right to evaluate, grant and revoke security certification in relation to ST products. These certification bodies are therefore independently responsible for granting or revoking security certification for an ST product, and ST does not take any responsibility for mistakes, evaluations, assessments, testing, or other activity carried out by the certification body with respect to any ST product.
- Industry-based cryptographic algorithms (such as AES, DES, or MD5) and other open standard technologies which may be used in conjunction with an ST product are based on standards which were not developed by ST. ST does not take responsibility for any flaws in such cryptographic algorithms or open technologies or for any methods which have been or may be developed to bypass, decrypt or crack such algorithms or technologies.
- While robust security testing may be done, no level of certification can absolutely guarantee protections against all attacks, including, for example, against advanced attacks which have not been tested for, against new or unidentified forms of attack, or against any form of attack when using an ST product outside of its specification or intended use, or in conjunction with other components or software which are used by customer to create their end product or application. ST is not responsible for resistance against such attacks. As such, regardless of the incorporated security features and/or any information or support that may be provided by ST, each customer is solely responsible for determining if the level of attacks tested for meets their needs, both in relation to the ST product alone and when incorporated into a customer end product or application.
- All security features of ST products (inclusive of any hardware, software, documentation, and the like), including but not limited to any enhanced security features added by ST, are provided on an "AS IS" BASIS. AS SUCH, TO THE EXTENT PERMITTED BY APPLICABLE LAW, ST DISCLAIMS ALL WARRANTIES, EXPRESS OR IMPLIED, INCLUDING BUT NOT LIMITED TO THE IMPLIED WARRANTIES OF MERCHANTABILITY OR FITNESS FOR A PARTICULAR PURPOSE, unless the applicable written and signed contract terms specifically provide otherwise.



ES0144 Rev 8 27/29

### 4 Revision history

**Table 5. Document revision history** 

Date	Revision	Changes
31-Jan-2011	1	Initial release.
29-Nov-2011	2	Added revision code 'T'.
20-Mar-2012	3	Added Section 2.7.6: Write in beCAN paged registers ignored.
08-Mar-2013	4	Added STM8AF62A6 part number to <i>Table 2: Device</i> summary.  Modified Section 2.7.1: beCAN transmission error when sleep mode is entered during transmission or reception.
06-Dec-2013	5	Added Section 2.1.6: Interrupt service routine (ISR) executed with priority of main process.  Added Section 2.2.4: RAM modified after reset by embedded bootloader.  Added Section 2.2.5: Flash / EEPROM memory is read incorrectly after wake-up from power- down mode.  Added Section 2.3.1: Corruption of read sequence for the 16-bit counter registers.
12-Apr-2016	6	Added Section 2.2.6: $V_{DD}$ rise-time rate for $100mV < V_{DD} < 1V$ .  Updated Table 2: Device summary to delete revision X products.  Deleted Appendix A.
22-Feb-2023	7	Updated Table 3: Product evolution summary (updated Section 2.6.2 title, added Section 2.6.3, Section 2.6.4 and Section 2.6.5)  "Limitations" removed in section titles  Modified order of sections (position of USART section changed)  Updated Section 2.6.2: Busy flag is unreliable when the SPI is a master simplex receive-only mode  Added Section 2.6.3: CRC may be corrupted by SPI configuration or other bus transfers, Section 2.6.4:  Anticipated communication upon SPI transit from slave receiver to master, and Section 2.6.5: BSY bit may stay high at the end of data transfer in slave mode  Added Section 3: Important security notice
26-Aug-2025	8	Added Section 2.2.7: Write access to EEPROM/flash may fail at high speeds and high temperatures



#### **IMPORTANT NOTICE - READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, please refer to <a href="https://www.st.com/trademarks">www.st.com/trademarks</a>. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2025 STMicroelectronics – All rights reserved



ES0144 Rev 8 29/29